

- buffer pin, 571
 built-in current sensor, 458
 built-in current testing, 458
 built-in logic block observer, 495, 497, 519
 built-in self-test, 36, 43, 466, 489
 burn-in, 20, 44
 burn-in coverage, 439
 burst mode, 318
 bus driver conflict, 552
 bus fault, 61
 bus-oriented BIST, 498
 Bushnell, 199, 406, 628
 Butler, 628
 BYPASS instruction, 564, 585
 bypass register, 553, 562, 564

 C cell, 583
 C-message filter, 373
 C-message weighting curve, 375
 CA, 511
 Ca, 581
 cache block, 298
 cache DRAM, 254, 296
 cache miss test, 298
 calculus of redundant faults, 200
 calibrate cell, 581
 calibration, 313, 590
 calibration error, 360
 Campbell, 627
 Capture-IR state, 571
 Case, 68, 78, 125
 CATAPULT, 204
 catastrophic analog fault, 387, 406
 catastrophic analog fault test, 391, 398, 399
 catastrophic fault, 314
 CCITT, 359, 372
 CDRAM, 254
 CE scaling, 14
 cell coupling fault, 63
 cell row, 475
 cellular automaton, 499, 511
 center frequency, 380
 central office, 366
 CF, 258, 266, 268
 CFdyn, 258, 269, 270
 CFid, 258, 270
 CFin, 258, 269
 CFS, 238
 Chakrabarty, 627
 Chakraborty, K., 626
 Chakraborty, T. J., 432
 Chakradhar, 164, 201, 203, 628
 Chakravarty, 626
 Chandra, 627
 Chang, 465, 625
 channel, 26
 channel-connected components, 93, 95
 characteristic polynomial, 505, 507, 516, 519
 characterization test, 18, 375, 390, 591
 Chatterjee, 396

 Chatopadhyay, 624
 checkpoint fault, 78
 checkpoint theorem, 78
 checksum test, 300
 chemical sensor, 613
 Chen, 628
 Cheng, K.-T., 239, 479, 481, 624, 626, 628
 Cheng, W.-T., 117, 219, 221
 chip level, 261
 Ciciani, 628
 circuit element, 398
 circuit level, 91, 93
 circuit-under-test, 24, 495
 circular fault masking, 64
 circular self-test path BIST, 525
 CLAMP instruction, 562, 587
 Clarke, 85, 625
 clipping level, 325
 clock, 212
 CLOCK cell, 571
 clock divider, 320
 clock fault, 214, 231
 clock rate, 10
 clock skew, 429
 ClockDR signal, 559, 560
 closest neighbor scan wiring, 478
 clustered defects, 45
 clustering parameter, 45, 49
 CMOS stuck-open fault, 274
 Co, 581
 CO (central office), 366
 CO (combinational observability), 131
 code format, 323
 code histogram, 326
 code polynomial, 616
 code word, 616
 CODEC, 366
 CODEC test, 375
 coder-decoder, 366
 coherence, 320
 coherence requirement, 339
 coherent correlation, 342
 coherent filtering, 342
 coherent measurement, 337
 coherent multi-tone testing, 356
 coherent sampling, 339
 coherent testing, 339
 collapse ratio, 74
 column decoder, 266
 combinational 0-controllability, 131
 combinational 1-controllability, 131
 combinational fault simulation complexity, 166
 combinational loop, 233
 combinational observability, 131
 combinational robust delay test, 433
 common-mode voltage, 592
 COMPACTEST, 206
 compaction, 513
 companion matrix, 505, 507